Quantitative Benchmarks for Energy Efficiency in Microelectronics



Challenges:

- Definition and quantification of metrics that consider other critical performance metrics can be challenging
 - Operations/Joule (computing)
 - Bits/Joule (communications)
 - Reliability and manufacturing metrics
- Methods to fairly compare different architectures
- Difficult to measure ultra-low-loss devices

Approach:

- Develop measurement techniques to verify energy consumption at the device level
- Enable validation of multi-scale, multi-physics models needed for design and evaluation of advanced energyefficient technologies
- Deploy *in-operando* measurements to identify dissipation/failure mechanisms

Impacts:

- Document demonstrated improvements in energy efficiency over time and enable quantitative comparisons among different approaches
- Deliver measurements, data, standards, and models to enable quantitative benchmarking
- Provide routes to add new validated energy-efficient approaches into semiconductor design cycles

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